

Application/Control No.	Applicant(s)/Patent under Reexamination
10/791,094	CHAN ET AL.
Examiner	Art Unit
Kevin Quinto	2826

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
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